## Amendments to the Claims:

The following listing replaces all prior listing of claims in the application.

## **Listing of Claims**

1. (Currently amended) A lithographic method comprising the pressing of a substrate, the method comprising:

preparing a substrate surface by forming a composite layer on the substrate, wherein forming the composite layer comprises forming an internal sub-layer of curable material in contact with the substrate surface and curing the internal sub-layer, and forming an external sub-layer adjacent to the cured internal sub-layer;

pressing a mold comprising a pattern of recesses and protrusions, wherein the protrusions of the mold penetrate into the external sub-layer until the protrusions contact the internal sub-layer;

performing at least one etching process in which the composite layer is etched by removing the internal sub-layer in regions defined by recesses formed in the external sub-layer until portions of a surface of the substrate have been exposed; and etching portions of the substrate exposed by the recesses using an etching pattern defined by the mold pattern

- 2. (Cancelled)
- 3. (Previously presented) The method according to claim 1, wherein forming the internal sub-layer and the external sub-layer comprise forming the same material.
- 4. (Previously presented) The method according to claim 1, wherein curing the internal sub-layer comprises heating the internal sub-layer at a temperature higher than a curing temperature of the internal sub-layer, and wherein pressing the mold comprises pressing at a pressing temperature higher than a glass transition temperature of the external sub-layer.

- 5. (Previously presented) The method according to claim 1, wherein forming the internal sub-layer of a curable material comprises forming a polymer.
- 6. (Previously presented) The method according to claim 1, wherein forming the internal sub-layer of a curable material comprises forming a resin configured to be cross-linked.
- 7. (Previously presented) The method according to claim 5, wherein forming the internal sub-layer of a curable material comprises forming one of a negative resin or a positive resin.
- 8. (Previously presented) The method according to claim 1, wherein forming the internal sub-layer comprises forming a sub-layer having a thickness of 0.01 micron to 1 micron.
- 9. (Previously presented) The method according to claim 1, wherein forming the external sub-layer comprises forming the external sub-layer to a thickness less than a depth of the pattern of recesses.
- 10. (Previously presented) The method according to claim 6, wherein forming a resin comprises forming one of a negative resin or a positive resin.
  - 11. (Currently amended) A lithographic method comprising:

forming a first layer on in contact with a surface of a substrate, the first layer comprising a curable material, and curing the first layer;

forming a second layer on the first layer, the second layer comprising a deformable material;

pressing a mold against the second layer, wherein protrusions of the mold form recesses in the second layer that expose portions of the first layer;

etching the exposed portions of the first layer using the second layer as an etch mask, and exposing surface regions of the substrate; and

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etching the surface regions of the substrate using at least the first layer as an etching mask.

12. (New) The method according to claim 11, wherein forming a first layer and a second layer comprise forming the same material.